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NTE74HC573 Integrated Circuit TTL – High Speed CMOS, Octal D–Type Latch with 3–State Outputs

Description:

The NTE74HC573 is a high speed octal transparent D–type latch with 3–state outputs in a 20–Lead DIP type package with the capability to drive 15 LS–TTL loads. When the latch–enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is low, the Q outputs are latched at the logic levels of the D inputs.

A buffered output–enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low) or the high–impedance state. In the high–impedance state, the outputs neither load nor drive the bus lines significantly. The high–impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

\overline{OE} does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high–impedance state.

To ensure the high–impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current–sinking capability of the driver.

Features:

- Wide Power Supply Range: 2V to 6V
- Three–State Outputs Directly Drive Bus Lines
- Balanced Propagation Delays and Transition Times
- Buffer Driver Outputs Drive up to 15 LS–TTL Loads
- Significant Power Reduction Compared to LS–TTL Logic ICs

Absolute Maximum Ratings: (Note 1, Note 2)

Supply Voltage, V_{CC}	–0.5 to +7.0V
Clamp Diode Current, I_{IK}, I_{OK}	±20mA
DC Drain Current (Per Output), I_{OUT}	±35mA
DC Output Source or Sink Current (Per Output), I_{OUT}	±25mA
DC V_{CC} or GND Current (Per Pin), I_{CC}	±50mA
Maximum Junction, T_J	+150°C
Storage Temperature Range, T_{stg}	–65°C to +150°C
Typical Thermal Resistance, Junction–to–Ambient, R_{thJA}	69°C/W
Lead Temperature (During Soldering, 10sec), T_L	+300°C

Note 1. Absolute Maximum Ratings are those values beyond which damage to the device may occur.

Note 2. Unless otherwise specified, all voltages are referenced to GND.

Recommended Operating Conditions: (Note 3)

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage	V_{CC}	2.0	-	6.0	V
High-Level Input Voltage $V_{CC} = 2.0V$ $V_{CC} = 4.5V$ $V_{CC} = 6.0V$	V_{IH}	1.5	-	-	V
		3.15	-	-	V
		4.2	-	-	V
Low-Level Input Voltage $V_{CC} = 2.0V$ $V_{CC} = 4.5V$ $V_{CC} = 6.0V$	V_{IL}	-	-	0.5	V
		-	-	1.35	V
		-	-	1.8	V
DC Input or Output Voltage	V_{IN}, V_{OUT}	0	-	V_{CC}	V
Input Rise or Fall Times $V_{CC} = 2.0V$ $V_{CC} = 4.5V$ $V_{CC} = 6.0V$	t_r, t_f	-	-	1000	ns
		-	-	500	ns
		-	-	400	ns

Note 3. All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.

DC Electrical Characteristics:

Parameter	Symbol	Test Conditions	V_{CC}	$T_A = +25^\circ C$		$T_A = -40^\circ \text{ to } +85^\circ C$		Unit
				Typ	Guaranteed Limits	Typ	Guaranteed Limits	
Minimum HIGH Level Output Voltage	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OUT} = -20\mu A$	-	V_{CC}	$V_{CC}^{-0.1}$	$V_{CC}^{-0.1}$	V
			$I_{OUT} = -6mA$	4.5	-	3.98	3.84	V
			$I_{OUT} = -7.8mA$	6.0	-	5.48	5.34	V
Minimum LOW Level Output Voltage	V_{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OUT} = 20\mu A$	-	-	0.1	0.1	V
			$I_{OUT} = 6mA$	4.5	0.2	0.26	0.33	V
			$I_{OUT} = 7.8mA$	6.0	0.2	0.26	0.33	V
Maximum Input Leakage Current	I_{IN}	$V_{IN} = V_{CC}$ or GND	6.0	-	± 0.1	± 1.0	μA	
Three-State Leakage Current	I_{OZ}	$V_{IN} = V_{IH}$ or V_{IL}	6.0	-	± 0.5	± 5.0	μA	
Maximum Quiescent Supply Current	I_{CC}	$V_{IN} = V_{CC}$ or GND, $I_{OUT} = 0\mu A$	6.0	-	8.0	80	μA	
Maximum Input Capacitance	C_{IN}		-	-	10	10	pF	
Maximum Output Capacitance	C_{OUT}		-	-	20	20	pF	
Power Dissipation Capacitance	C_{PD}		5	51	-	-	pF	

Prerequisite for Switching Specifications:

Parameter	Symbol	Test Conditions	V_{CC}	$T_A = +25^\circ C$		$T_A = -40^\circ \text{ to } +85^\circ C$		Unit
				Typ	Guaranteed Limits	Typ	Guaranteed Limits	
Pulse Duration (LE High)	t_w		2.0	-	80	100	ns	
			4.5	-	16	20	ns	
			6.0	-	14	17	ns	
Setup Time (Data before LE \downarrow)	t_{SU}		2.0	-	50	65	ns	
			4.5	-	10	13	ns	
			6.0	-	9	11	ns	
Hold Time (Data after LE \downarrow)	t_H		2.0	-	40	50	ns	
			4.5	-	8	10	ns	
			6.0	-	7	9	ns	

Switching Characteristics: ($C_L = 50\text{pF}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	V_{CC}	$T_A = +25^\circ\text{C}$		$T_A = -40^\circ \text{ to } +85^\circ\text{C}$		Unit
				Typ	Guaranteed Limits			
Propagation Delay Time (From Input D to Output Q)	t_{pd}		2.0	–	175	220	ns	
			4.5	–	35	44	ns	
			6.0	–	30	37	ns	
Propagation Delay Time (From Input LE to Output Q)	t_{pd}		2.0	–	175	220	ns	
			4.5	–	35	44	ns	
			6.0	–	30	37	ns	
Output Enable and Disable Time (From Input \overline{OE} to Output Q)	t_{en}, t_{dis}		2.0	–	150	190	ns	
			4.5	–	30	38	ns	
			6.0	–	26	33	ns	
Output Transition Time (To Output Q)	t_t		2.0	–	60	75	ns	
			4.5	–	12	15	ns	
			6.0	–	10	13	ns	

Truth Table:

Inputs			Output
\overline{OE}	LE	D	Q
L	H	H	H
L	H	L	L
L	L	X	Q0
H	X	X	Z

H = HIGH Level (Steady State)

L = LOW Level (Steady State)

X = Don't Care

Q0 = The level of Q before the indicated steady state input conditions were established.

Z = High Impedance State

Pin Connection Diagram

